

FIG. 1. (a) XRD patterns (log scale) for  $\kappa$ -Ga<sub>2</sub>O<sub>3</sub> films grown on c-plane sapphire substrates by HVPE and MOCVD (b) Corresponding XRD rocking curves for the (004) symmetric diffraction peaks of  $\kappa$ -Ga<sub>2</sub>O<sub>3</sub>

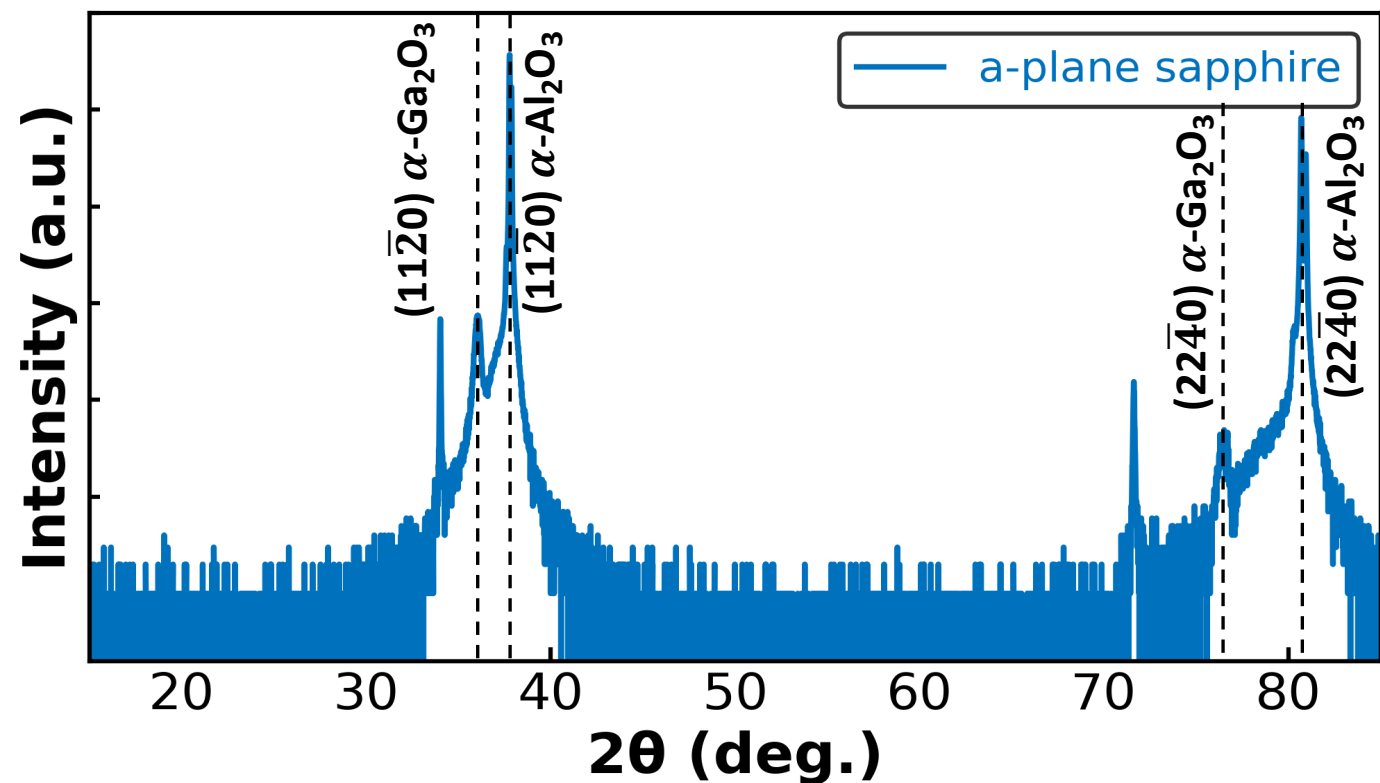


FIG. 2. XRD pattern (log scale) for  $\alpha$ -Ga<sub>2</sub>O<sub>3</sub> films grown on a-plane sapphire substrate by HVPE